

SEMICONDUCTOR®

## FDZ661PZ

#### December 2011

# P-Channel 1.5 V Specified PowerTrench<sup>®</sup> Thin WL-CSP MOSFET -20 V, -2.6 A, 140 m $\Omega$

### Features

- Max  $r_{DS(on)}$  = 140 m $\Omega$  at V<sub>GS</sub> = -4.5 V, I<sub>D</sub> = -2 A
- Max  $r_{DS(on)}$  = 182 m $\Omega$  at V<sub>GS</sub> = -2.5 V, I<sub>D</sub> = -1.5 A
- Max r<sub>DS(on)</sub> = 231 mΩ at V<sub>GS</sub> = -1.8 V, I<sub>D</sub> = -1 A
- Max r<sub>DS(on)</sub> = 315 mΩ at V<sub>GS</sub> = -1.5 V, I<sub>D</sub> = -1 A
- Occupies only 0.64 mm<sup>2</sup> of PCB area. Less than 16% of the area of 2 x 2 BGA
- Ultra-thin package: less than 0.4 mm height when mounted to PCB
- HBM ESD protection level > 2 kV (Note3)
- RoHS Compliant

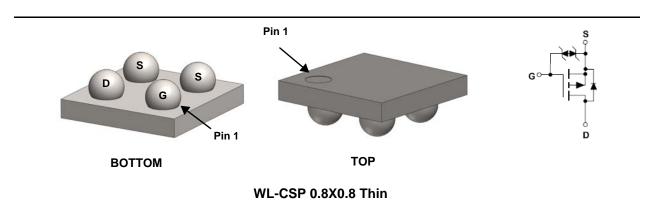


## **General Description**

Designed on Fairchild's advanced 1.5 V PowerTrench<sup>®</sup> process with state of the art "fine pitch" Thin WLCSP packaging process, the FDZ661PZ minimizes both PCB space and  $r_{DS(on)}$ . This advanced WLCSP MOSFET embodies a breakthrough in packaging technology which enables the device to combine excellent thermal transfer characteristics, ultra-low profile (0.4 mm) and small (0.8x0.8 mm<sup>2</sup>) packaging, low gate charge, and low  $r_{DS(on)}$ .

## Applications

- Battery management
- Load switch
- Battery protection



## **MOSFET Maximum Ratings** T<sub>A</sub> = 25 °C unless otherwise noted

Symbol	Para	meter		Ratings	Units
V <sub>DS</sub>	Drain to Source Voltage			-20	V
V <sub>GS</sub>	Gate to Source Voltage			±8	V
I <sub>D</sub>	-Continuous	T <sub>A</sub> = 25 °C	(Note 1a)	-2.6	•
	-Pulsed			-10	— A
P <sub>D</sub>	Power Dissipation	T <sub>A</sub> = 25 °C	(Note 1a)	1.3	14/
	Power Dissipation	T <sub>A</sub> = 25 °C	(Note 1b)	0.4	W
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range			-55 to +150	°C

#### **Thermal Characteristics**

$R_{ ext{ heta}JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	93	°C/W
$R_{ extsf{ heta}JA}$	Thermal Resistance, Junction to Ambient	(Note 1b)	311	C/W

#### Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
EH	FDZ661PZ	WL-CSP 0.8X0.8 Thin	7 "	8 mm	5000 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units	
Off Chara	acteristics						
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	I <sub>D</sub> = -250 μA, V <sub>GS</sub> = 0 V	-20			V	
$\Delta BV_{DSS}$ $\Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = -250 \ \mu\text{A}$ , referenced to 25 °C		-13		mV/°C	
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = -16 V, V_{GS} = 0 V$			-1	μΑ	
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 8 \text{ V}, V_{DS} = 0 \text{ V}$			±6	μΑ	
On Chara	octeristics						
V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = -250 \ \mu A$	-0.3	-0.7	-1.2	V	
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = -250 \ \mu$ A, referenced to 25 °C		2.5		mV/°C	
r <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = -4.5 \text{ V}, I_D = -2 \text{ A}$		108	140	mΩ	
		V <sub>GS</sub> = -2.5 V, I <sub>D</sub> = -1.5 A		129	182		
		$V_{GS} = -1.8 \text{ V}, I_D = -1 \text{ A}$		159	231		
		$V_{GS} = -1.5 \text{ V}, I_D = -1 \text{ A}$		201	315		
		$V_{GS}$ = -4.5 V, I <sub>D</sub> = -2 A, T <sub>J</sub> =125°C		143	204		
9fs	Forward Transconductance	$V_{DD} = -5 V, I_D = -2 A$		7.8		S	
Dynamic	Characteristics						
C <sub>iss</sub>	Input Capacitance			416	555	pF	
C <sub>oss</sub>	Output Capacitance	──V <sub>DS</sub> = -10 V, V <sub>GS</sub> = 0 V, f = 1 MHz		61	80	pF	
C <sub>rss</sub>	Reverse Transfer Capacitance			53	70	pF	
	g Characteristics						
t <sub>d(on)</sub>	Turn-On Delay Time			4.9	10	ns	
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = -10 V, I <sub>D</sub> = -2.5 A,		6.3	13	ns	
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = -4.5 \text{ V}, \text{ R}_{GEN} = 6 \Omega$		68	108	ns	
t <sub>f</sub>	Fall Time			33	52	ns	
Q <sub>g</sub>	Total Gate Charge			6.3	8.8	nC	
Q <sub>gs</sub>	Gate to Source Charge	$V_{GS} = -4.5 \text{ V}, \text{ V}_{DD} = -10 \text{ V},$ $I_{D} = -2.5 \text{ A}$		0.6		nC	
Q <sub>gd</sub>	Gate to Drain "Miller" Charge			1.7		nC	

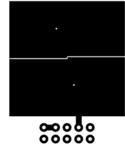
Notes:

t<sub>rr</sub>

Q<sub>rr</sub>

1. R<sub>0JA</sub> is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>0JC</sub> is guaranteed by design while R<sub>0CA</sub> is determined by the user's board design.

I<sub>F</sub> = -2.5 A, di/dt = 100 A/μs



a. 93 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



b. 311 °C/W when mounted on a minimum pad of 2 oz copper.

29

10

46

18

ns

nC

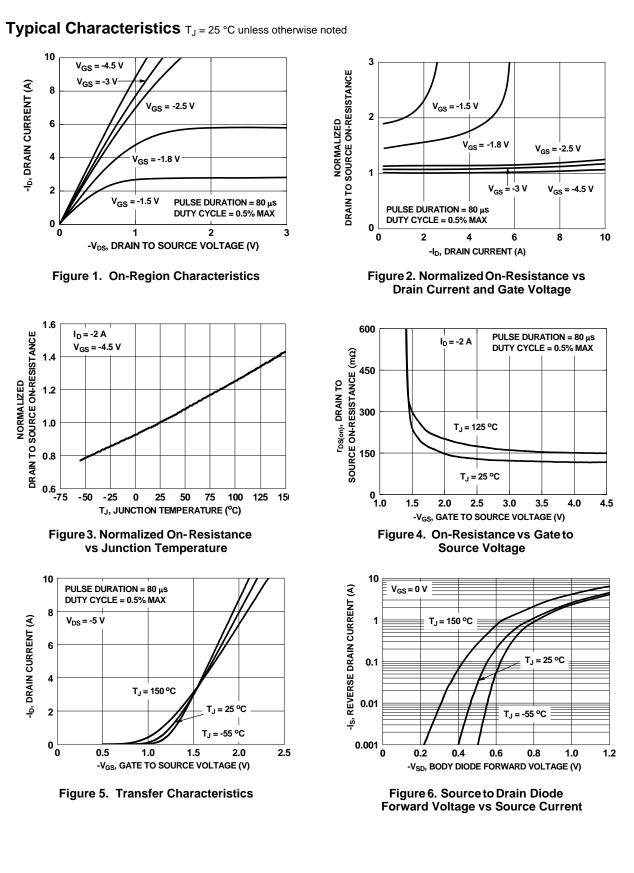
2. Pulse Test: Pulse Width < 300  $\mu s,$  Duty cycle < 2.0%.

Reverse Recovery Time

Reverse Recovery Charge

3. The diode connected between the gate and source serves only as protection ESD. No gate overvoltage rating is implied.

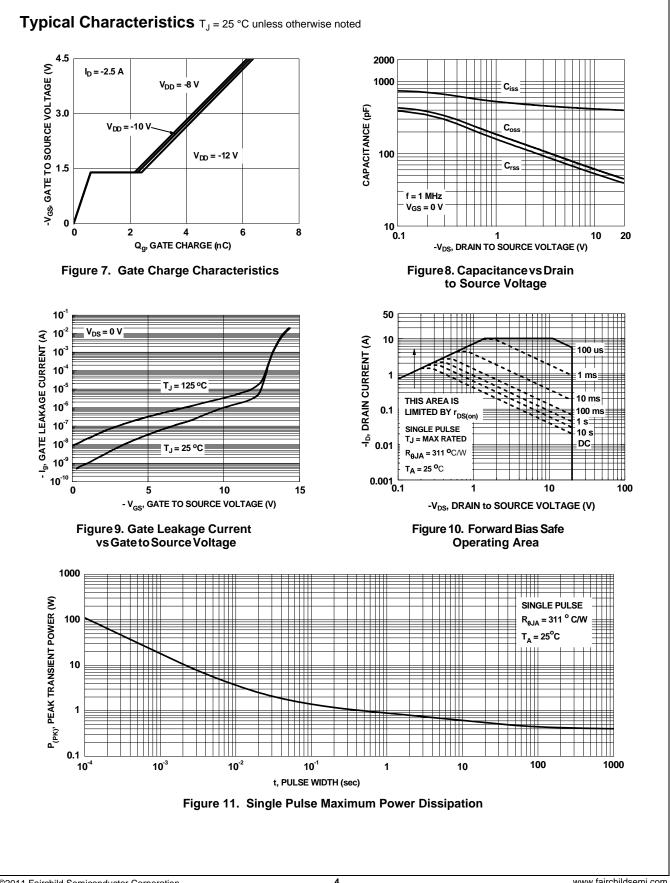
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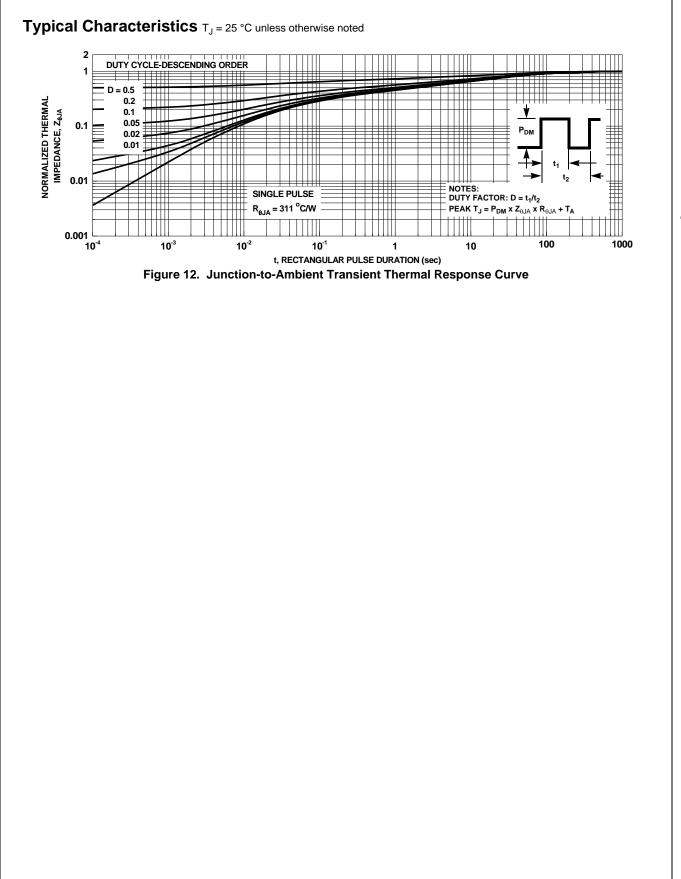
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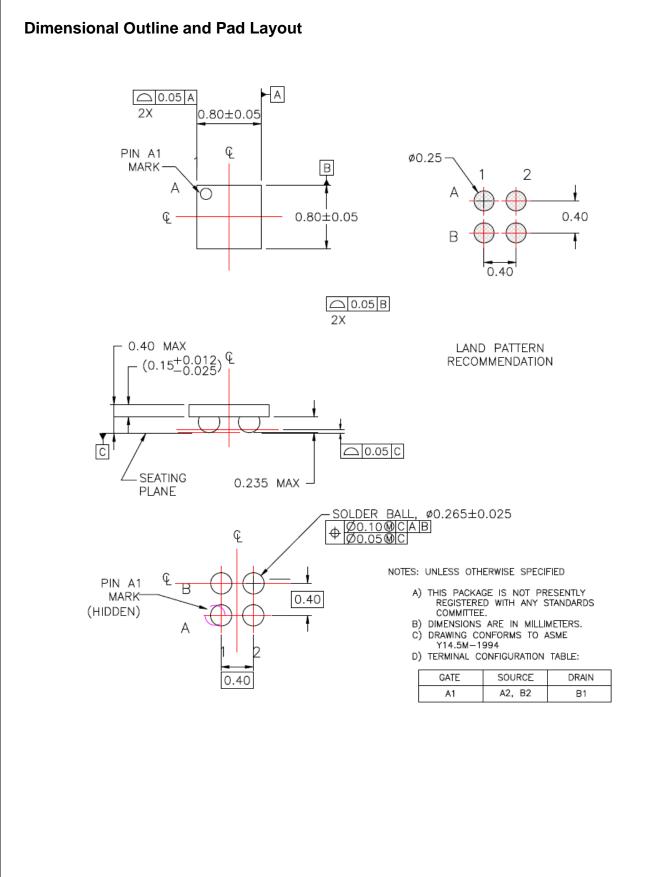
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